

Tetrakis(4-methyl-2-thienyl)tin(IV)

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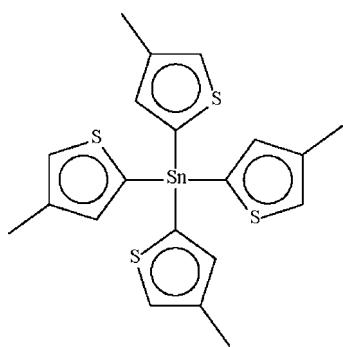
Received 10 September 2008; accepted 10 October 2008

Key indicators: single-crystal X-ray study; $T = 100$ K; mean $\sigma(\text{C}-\text{C}) = 0.002 \text{ \AA}$; R factor = 0.012; wR factor = 0.028; data-to-parameter ratio = 19.8.

The molecule of the title compound, $[\text{Sn}(\text{C}_5\text{H}_5\text{S})_4]$, lies on a special position of $\bar{4}$ site symmetry. The Sn^{IV} atom shows a slightly distorted tetrahedral coordination.

Related literature

For the structure of tetrakis(2-thienyl)tin, see: Karipides *et al.* (1977). For the synthesis, see: Kumar Das *et al.* (1987).



Experimental

Crystal data

$[\text{Sn}(\text{C}_5\text{H}_5\text{S})_4]$
 $M_r = 507.29$

Tetragonal, $I\bar{4}$
 $a = 11.6286 (9) \text{ \AA}$

$c = 7.5918 (6) \text{ \AA}$
 $V = 1026.6 (1) \text{ \AA}^3$
 $Z = 2$
Mo $K\alpha$ radiation

$\mu = 1.65 \text{ mm}^{-1}$
 $T = 100 (2) \text{ K}$
 $0.30 \times 0.25 \times 0.10 \text{ mm}$

Data collection

Bruker SMART APEX
diffractometer
Absorption correction: multi-scan
(*SADABS*; Sheldrick, 1996)
 $T_{\min} = 0.637$, $T_{\max} = 0.852$

2948 measured reflections
1151 independent reflections
1149 reflections with $I > 2\sigma(I)$
 $R_{\text{int}} = 0.014$

Refinement

$R[F^2 > 2\sigma(F^2)] = 0.012$
 $wR(F^2) = 0.028$
 $S = 1.01$
1151 reflections
58 parameters
H-atom parameters constrained

$\Delta\rho_{\text{max}} = 0.45 \text{ e \AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.21 \text{ e \AA}^{-3}$
Absolute structure: Flack (1983),
513 Friedel pairs
Flack parameter: 0.005 (14)

Data collection: *APEX2* (Bruker, 2007); cell refinement: *SAINT* (Bruker, 2007); data reduction: *SAINT*; program(s) used to solve structure: *SHELXS97* (Sheldrick, 2008); program(s) used to refine structure: *SHELXL97* (Sheldrick, 2008); molecular graphics: *X-SEED* (Barbour, 2001); software used to prepare material for publication: *publCIF* (Westrip, 2008).

The authors thank the University of Malaya for funding this study (grant No. FR155/2007A) and also for the purchase of the diffractometer.

Supplementary data and figures for this paper are available from the IUCr electronic archives (Reference: CI2670).

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Acta Cryst. (2008). E64, m1410 [doi:10.1107/S1600536808032790]

Tetrakis(4-methyl-2-thienyl)tin(IV)

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Experimental

The title compound was synthesized as reported previously (Kumar Das *et al.*, 1987). Single crystals were obtained upon recrystallization from chloroform.

Refinement

H-atoms were placed in calculated positions ($C-H = 0.95\text{--}0.98 \text{ \AA}$) and were included in the refinement in the riding model approximation, with $U(H)$ set to $1.2\text{--}1.5 U_{\text{eq}}(C)$.

Figures

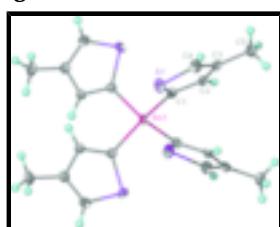


Fig. 1. Displacement ellipsoid plot (Barbour, 2001) of $[\text{Sn}(\text{C}_5\text{H}_5\text{S})_4]$ at the 70% probability level. H atoms are drawn as spheres of arbitrary radii.

Tetrakis(4-methyl-2-thienyl)tin(IV)

Crystal data

$[\text{Sn}(\text{C}_5\text{H}_5\text{S})_4]$	$Z = 2$
$M_r = 507.29$	$F_{000} = 508$
Tetragonal, $I\bar{4}$	$D_x = 1.641 \text{ Mg m}^{-3}$
Hall symbol: I -4	Mo $K\alpha$ radiation
$a = 11.6286 (9) \text{ \AA}$	$\lambda = 0.71073 \text{ \AA}$
$b = 11.6286 \text{ \AA}$	Cell parameters from 2958 reflections
$c = 7.5918 (6) \text{ \AA}$	$\theta = 2.5\text{--}28.3^\circ$
$\alpha = 90^\circ$	$\mu = 1.65 \text{ mm}^{-1}$
$\beta = 90^\circ$	$T = 100 (2) \text{ K}$
$\gamma = 90^\circ$	Prism, colourless
$V = 1026.6 (1) \text{ \AA}^3$	$0.30 \times 0.25 \times 0.10 \text{ mm}$

Data collection

Bruker SMART APEX diffractometer	1151 independent reflections
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Radiation source: fine-focus sealed tube	1149 reflections with $I > 2\sigma(I)$
Monochromator: graphite	$R_{\text{int}} = 0.014$
$T = 100(2)$ K	$\theta_{\text{max}} = 27.5^\circ$
ω scans	$\theta_{\text{min}} = 2.5^\circ$
Absorption correction: multi-scan (SADABS; Sheldrick, 1996)	$h = -15 \rightarrow 14$
$T_{\text{min}} = 0.637$, $T_{\text{max}} = 0.852$	$k = -15 \rightarrow 13$
2948 measured reflections	$l = -9 \rightarrow 8$

Refinement

Refinement on F^2	Hydrogen site location: inferred from neighbouring sites
Least-squares matrix: full	H-atom parameters constrained
$R[F^2 > 2\sigma(F^2)] = 0.012$	$w = 1/[\sigma^2(F_o^2) + (0.0145P)^2]$ where $P = (F_o^2 + 2F_c^2)/3$
$wR(F^2) = 0.028$	$(\Delta/\sigma)_{\text{max}} = 0.001$
$S = 1.01$	$\Delta\rho_{\text{max}} = 0.45 \text{ e \AA}^{-3}$
1151 reflections	$\Delta\rho_{\text{min}} = -0.21 \text{ e \AA}^{-3}$
58 parameters	Extinction correction: none
Primary atom site location: structure-invariant direct methods	Absolute structure: Flack (1983), 513 Friedel pairs
Secondary atom site location: difference Fourier map	Flack parameter: 0.005 (14)

Fractional atomic coordinates and isotropic or equivalent isotropic displacement parameters (\AA^2)

	x	y	z	$U_{\text{iso}}^*/U_{\text{eq}}$
Sn1	0.5000	0.5000	0.5000	0.01202 (5)
S1	0.36597 (3)	0.74692 (3)	0.61422 (5)	0.02012 (9)
C1	0.46144 (12)	0.63979 (12)	0.6694 (2)	0.0140 (3)
C2	0.50206 (12)	0.65832 (13)	0.8364 (2)	0.0134 (3)
H2	0.5562	0.6088	0.8914	0.016*
C3	0.45677 (14)	0.75770 (14)	0.9212 (2)	0.0154 (3)
C4	0.38176 (14)	0.81447 (13)	0.8139 (2)	0.0192 (3)
H4	0.3429	0.8832	0.8459	0.023*
C5	0.48542 (16)	0.79485 (16)	1.1056 (2)	0.0206 (4)
H5A	0.4919	0.8788	1.1097	0.031*
H5B	0.5586	0.7602	1.1414	0.031*
H5C	0.4244	0.7697	1.1859	0.031*

Atomic displacement parameters (\AA^2)

	U^{11}	U^{22}	U^{33}	U^{12}	U^{13}	U^{23}
Sn1	0.01360 (6)	0.01360 (6)	0.00885 (9)	0.000	0.000	0.000
S1	0.0221 (2)	0.0223 (2)	0.0160 (2)	0.00775 (16)	-0.00468 (16)	0.00016 (16)
C1	0.0138 (7)	0.0138 (7)	0.0144 (8)	0.0010 (5)	0.0011 (6)	0.0019 (6)
C2	0.0133 (6)	0.0140 (7)	0.0129 (8)	0.0000 (5)	0.0011 (6)	0.0020 (6)
C3	0.0165 (8)	0.0151 (8)	0.0146 (8)	-0.0017 (6)	0.0023 (6)	0.0011 (6)

C4	0.0220 (8)	0.0172 (8)	0.0185 (9)	0.0055 (6)	0.0014 (7)	-0.0008 (7)
C5	0.0267 (9)	0.0213 (9)	0.0139 (9)	-0.0005 (7)	0.0007 (7)	-0.0030 (7)

Geometric parameters (\AA , $^\circ$)

Sn1—C1 ⁱ	2.1209 (15)	C2—H2	0.95
Sn1—C1	2.1209 (15)	C3—C4	1.364 (2)
Sn1—C1 ⁱⁱ	2.1209 (15)	C3—C5	1.502 (2)
Sn1—C1 ⁱⁱⁱ	2.1209 (15)	C4—H4	0.95
S1—C4	1.7173 (16)	C5—H5A	0.98
S1—C1	1.7206 (15)	C5—H5B	0.98
C1—C2	1.370 (2)	C5—H5C	0.98
C2—C3	1.424 (2)		
C1 ⁱ —Sn1—C1	111.58 (4)	C4—C3—C2	111.07 (15)
C1 ⁱ —Sn1—C1 ⁱⁱ	105.32 (8)	C4—C3—C5	124.00 (16)
C1—Sn1—C1 ⁱⁱ	111.58 (4)	C2—C3—C5	124.92 (16)
C1 ⁱ —Sn1—C1 ⁱⁱⁱ	111.58 (4)	C3—C4—S1	111.98 (12)
C1—Sn1—C1 ⁱⁱⁱ	105.32 (8)	C3—C4—H4	124.0
C1 ⁱⁱ —Sn1—C1 ⁱⁱⁱ	111.58 (4)	S1—C4—H4	124.0
C4—S1—C1	92.70 (8)	C3—C5—H5A	109.5
C2—C1—S1	109.51 (12)	C3—C5—H5B	109.5
C2—C1—Sn1	127.51 (11)	H5A—C5—H5B	109.5
S1—C1—Sn1	122.93 (8)	C3—C5—H5C	109.5
C1—C2—C3	114.74 (14)	H5A—C5—H5C	109.5
C1—C2—H2	122.6	H5B—C5—H5C	109.5
C3—C2—H2	122.6		
C4—S1—C1—C2	0.03 (12)	S1—C1—C2—C3	0.28 (17)
C4—S1—C1—Sn1	177.81 (9)	Sn1—C1—C2—C3	-177.37 (11)
C1 ⁱ —Sn1—C1—C2	149.39 (12)	C1—C2—C3—C4	-0.54 (19)
C1 ⁱⁱ —Sn1—C1—C2	-93.09 (10)	C1—C2—C3—C5	178.39 (14)
C1 ⁱⁱⁱ —Sn1—C1—C2	28.15 (11)	C2—C3—C4—S1	0.54 (17)
C1 ⁱ —Sn1—C1—S1	-27.98 (10)	C5—C3—C4—S1	-178.40 (12)
C1 ⁱⁱ —Sn1—C1—S1	89.54 (12)	C1—S1—C4—C3	-0.34 (13)
C1 ⁱⁱⁱ —Sn1—C1—S1	-149.22 (11)		

Symmetry codes: (i) $-y+1, x, -z+1$; (ii) $y, -x+1, -z+1$; (iii) $-x+1, -y+1, z$.

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Fig. 1

